



IFW

PATENT  
8075-1014

**IN THE U.S. PATENT AND TRADEMARK OFFICE**

Applicants: Tsuguo FUKUDA et al. Confirmation: 4391  
Serial No.: 10/551,113 Art Unit: 1743  
Filed: Sept. 28, 2005 Examiner: Not assigned  
For: METHOD FOR ANALYZING IMPURITIES (COLOR CENTERS) OF  
FLUORIDE AND PROCESS FOR PRODUCING MATERIAL FOR  
GROWING SINGLE CRYSTAL

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**September 1, 2006**

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, included with the attached Form PTO-1449 is the English language translation of the International Preliminary Examination Report (IPER), together with copies of two references that were not cited in the International Search Report included with the Information Disclosure Statement (IDS) filed with the present application on September 28, 2005.

The Examiner is courteously requested to initial and return a copy of the attached Form PTO-1449 to confirm consideration of the references and their entry into the record.

Respectfully submitted,

YOUNG & THOMPSON

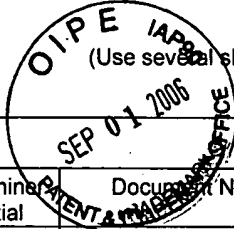
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**INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION**

(Use several sheets if necessary)



Attorney Docket No.:

**8075-1014**

Application No.:

**10/551,113**

Applicant:

**Tsuguo FUKUDA, et al.**

Filing Date:

**September 28, 2005**

Group Art Unit:

**1743**
**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)

**FOREIGN PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	64-10450 U	01-19-1989	JAPAN			*	
	2820367 B2	08-28-1998	JAPAN			Yes	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**


EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* English language abstract provided for the Examiner's convenience

BC:lpp:rk